



Form PTO 1449  
(Modified)

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

PATENT DOCKET NO.

242927US90

SERIAL NO.

10/663,730

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Hajime NOTO, et al.

FILING DATE

September 17, 2003

GROUP

2873

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
SCC	AA	5,923,380	07/13/1999	Yibing YANG, et al.			
	AB						
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

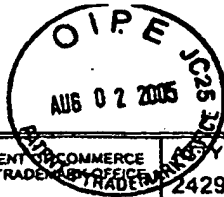
Examiner

/Sheela Chawan/

Date Considered

12/26/2006

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



SHEET 1 OF 1

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## FOREIGN PATENT DOCUMENTS

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SCC	AO	2000-146543	05/26/2000	Japan (with English Abstract)		x
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☐ Additional References sheet(s) attached

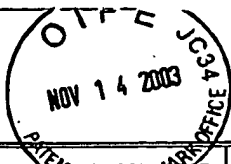
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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 242927US90		SERIAL NO. 10/663,730	
<div style="border: 2px solid black; border-radius: 50%; padding: 10px; display: inline-block;"> <b>PTO</b>  <b>JUL 05 2005</b>  <b>PATENT &amp; TRADEMARK OFFICE</b> </div>				APPLICANT Hajime NOTO, et al.			
				FILING DATE September 17, 2003		GROUP 2873	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
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	AR						
	AS						
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	AU						
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<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
SCC	AW	C. Marc BASTUSCHECK, "Techniques for Real-time Generation of Range Images", IEEE Computer Society Conference, XP-010016459, June 4, 1989, pages 262-268					
↓	AX	C. Marc BASTUSCHECK, et al., "Object Recognition by Three-Dimensional Curve Matching", International Journal of Intelligent Systems, vol. 1, XP-009047871, 1986, pages 105-132,					
↓	AY	Brian CARRIHILL, et al., "Experiments with the Intensity Ratio Depth Sensor", Computer Vision, Graphics and Image Processing, vol. 32, XP-009047858, 1985, pages 337-358					
↓	AZ	Jose R. A. TORREAO, "A New Approach to Photometric Stereo", ELSEVIER, Pattern Recognition Letters, vol. 20, no. 5, XP-004169879, May 1999, Pages 535-540				<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Sheela Chawan/				Date Considered      12/26/2006			
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SHEET 1 OF 1

Form PTO 1449  
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ATTY DOCKET NO.

242927US2

SERIAL NO.

10/663,730

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Hajime NOTO, et al.

FILING DATE

September 17, 2003

GROUP

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
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## FOREIGN PATENT DOCUMENTS

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/SCC/	AO	2000-329524	11/30/2000	JAPAN (with English Abstract)		X
	AP	2000-121339	04/28/2000	JAPAN (with English Abstract)		X
↓	AQ	2-79179	03/19/1990	JAPAN (with English Abstract)		X
↓	AR	2002-358519	12/13/2002	JAPAN (with English Abstract)		X
↓	AS	11-134505	05/21/1999	JAPAN (with English Abstract)		X
	AT					
	AU					
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## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 242927US40		SERIAL NO. 10/663,730	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hajime NOTO, et al.			
				FILING DATE September 17, 2003		GROUP 2624	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
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	AQ						
	AR						
	AS						
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